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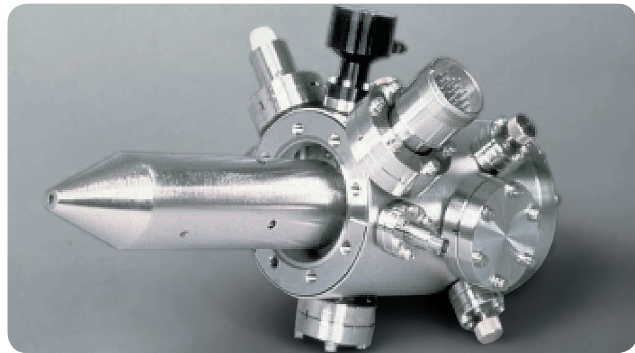
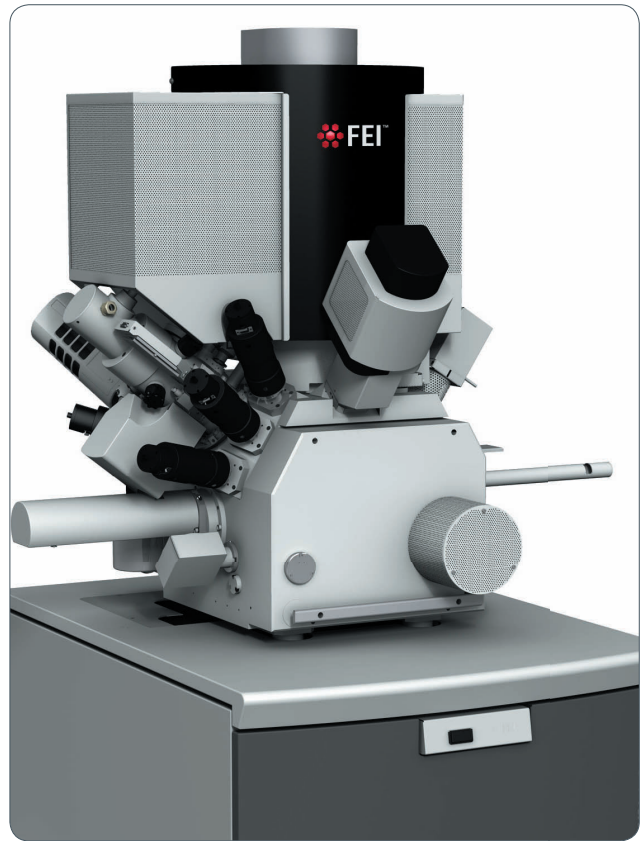
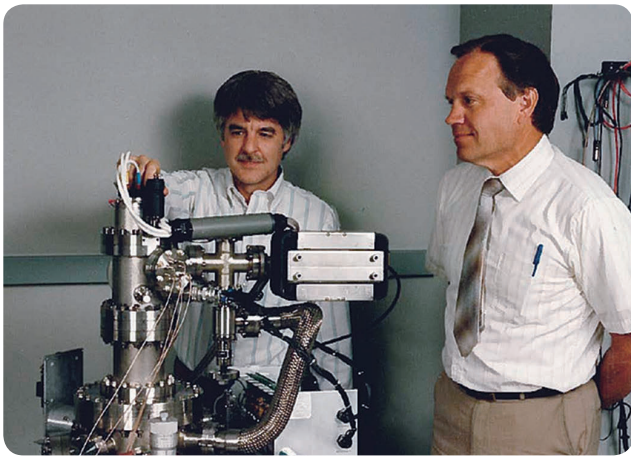
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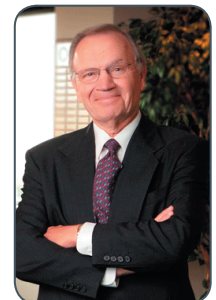
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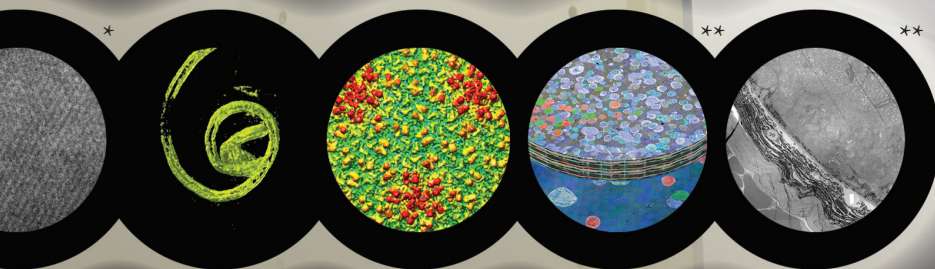
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April 2014

***IN SITU* SPECIAL SECTION**

Introduction: Special Issue on Electron Microscopy of Specimens in Liquid 315
Niels de Jonge

In Situ Imaging of Nano-Droplet Condensation and Coalescence on Thin Water Films 317
Zahava Barkay

X-ray Energy-Dispersive Spectrometry During *In Situ* Liquid Cell Studies Using an Analytical Electron Microscope 323
Nestor J. Zaluzec, M. Grace Burke, Sarah J. Haigh, and Matthew A. Kulzick

In Situ Cryogenic Transmission Electron Microscopy for Characterizing the Evolution of Solidifying Water Ice in Colloidal Systems 330
Kaiping Tai, Yin Liu, and Shen J. Dillon

Improved Microchip Design and Application for *In Situ* Transmission Electron Microscopy of Macromolecules 338
Madeline J. Dukes, Rebecca Thomas, John Damiano, Kate L. Klein, Sharavanan Balasubramaniam, Sanem Kayandan, Judy S. Riffle, Richey M. Davis, Sarah M. McDonald, and Deborah F. Kelly

Liquid Scanning Transmission Electron Microscopy: Imaging Protein Complexes in their Native Environment in Whole Eukaryotic Cells 346
Diana B. Peckys and Niels de Jonge

Wet-STEM Tomography: Principles, Potentialities and Limitations 366
Karine Masenelli-Varlot, Annie Malchère, José Ferreira, Hamed Heidari Mezerji, Sara Bals, Cédric Messaoudi, and Sergio Marco Garrido

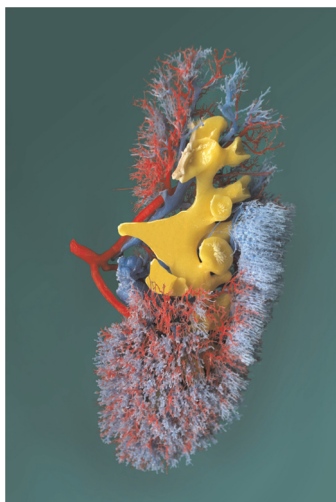
Liquid Phase Electron-Beam-Induced Deposition on Bulk Substrates Using Environmental Scanning Electron Microscopy 376
Matthew Bresin, Aurelien Botman, Steven J Randolph, Marcus Straw, and Jeffrey Todd Hastings

In-situ WetSTEM Observation of Gold Nanorod Self-assembly Dynamics in a Drying Colloidal Droplet 385
Filip Novotný, Petr Wandrol, Jan Proška, and Miroslav Šlouf

Novel Method for Visualizing Water Transport Through Phase-Separated Polymer Films 394
Anna Jansson, Catherine Boissier, Mariagrazia Marucci, Mark Nicholas, Stefan Gustafsson, Anne-Marie Hermansson, and Eva Olsson

Nucleation Dynamics of Water Nanodroplets 407
Dipanjan Bhattacharya, Michel Bosman, V.R.S.S Mokkalapati, Fong Yew Leong, and Utkur Mirsaidov

Visualization of the Coalescence of Bismuth Nanoparticles 416
Kai-Yang Niu, Hong-Gang Liao, and Haimei Zheng



On the Cover: Corrosion cast of pig kidney. For further information see Haenssger et al., pp. 493–513.

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Investigating Processes of Nanocrystal Formation and Transformation Via Liquid Cell TEM	425
<i>Michael H. Nielsen, Dongsheng Li, Hengzhong Zhang, Shaul Aloni, Thomas Y.J. Han, Cathrine Frandsen, Jong Seto, Jillian F. Banfield, Helmut Cölfen, and James J. De Yoreo</i>	
Drying Effect Creates False Assemblies in DNA-Coated Gold Nanoparticles as Determined Through <i>In Situ</i> Liquid Cell STEM	437
<i>Angela R. Rudolph, Katherine L. Jungjohann, David R. Wheeler, and Susan M. Brozik</i>	
Monolithic Chip System with a Microfluidic Channel for <i>In-situ</i> Electron Microscopy of Liquids	445
<i>Eric Jensen, Andrew Burrows, and Kristian Mølhave</i>	
Quantitative Electrochemical Measurements Using <i>In Situ</i> ec-S/TEM Devices	452
<i>Raymond R. Unocic, Robert L. Sacci, Gilbert M. Brown, Gabriel M. Veith, Nancy J. Dudley, Karren L. More, Franklin S. Walden II, Daniel S. Gardiner, John Damiano, and David P. Nackashi</i>	
Metastable Structures in Al Thin Films Prior to the Onset of Corrosion Pitting as Observed using Liquid Cell Transmission Electron Microscopy	462
<i>See Wee Chee, David J. Duquette, Frances M. Ross, and Robert Hull</i>	
Immuno-Electron Microscopy of Primary Cell Cultures from Genetically Modified Animals in Liquid by Atmospheric Scanning Electron Microscopy	469
<i>Takaaki Kinoshita, Yosio Mori, Kazumi Hirano, Shinya Sugimoto, Ken-ichi Okuda, Shunsuke Matsumoto, Takeshi Namiki, Tatsuhiko Ebihara, Masaaki Kawata, Hidetoshi Nishiyama, Mari Sato, Mitsuo Suga, Kenichi Higashiyama, Kenji Sonomoto, Yoshimitsu Mizunoe, Shoko Nishihara, and Chikara Sato</i>	
<i>In-Situ</i> Electrochemical Transmission Electron Microscopy for Battery Research	484
<i>B. Layla Mehdi, Meng Gu, Lucas R. Parent, Wu Xu, E. N. Nasybulin, Xilin Chen, Raymond R. Unocic, Pinghong Xu, David Welch., Patricia Abellan, Ji-Guang Zhang, Jun Liu, Chong-Min Wang, Ilke Arslan, James Evans, and Nigel D. Browning</i>	

BIOLOGICAL APPLICATIONS

REVIEW ARTICLE

Casting Materials and their Application in Research and Teaching	493
<i>Kati Haenssger, Andrew N. Makanya, and Valentin Djonov</i>	
Identifying Dynamic Membrane Structures with Atomic-Force Microscopy and Confocal Imaging	514
<i>Tobias Timmel, Markus Schuelke, and Simone Spuler</i>	
Electron and Force Microscopy Characterization of Particle Size Effects and Surface Phenomena Associated with Individual Natural Organic Matter Fractions	521
<i>Lee W. Hoffman, Gabriela Chilom, Swaminathan Venkatesan, and James A. Rice</i>	
Synchrotron-Based Chemical Nano-Tomography of Microbial Cell-Mineral Aggregates in their Natural, Hydrated State	531
<i>Gregor Schmid, Fabian Zeitvogel, Likai Hao, Pablo Ingino, Wolfgang Kuerner, James J. Dynes, Chithra Karunakaran, Jian Wang, Yingshen Lu, Travis Ayers, Chuck Schietinger, Adam P. Hitchcock, and Martin Obst</i>	
Nanoscale Focused Ion Beam Tomography of Single Bacterial Cells for Assessment of Antibiotic Effects	537
<i>Boyin Liu, Heidi H. Yu, Tuck Wah Ng, David L. Paterson, Tony Velkov, Jian Li, and Jing Fu</i>	

Combined Scanning Transmission Electron4 Microscopy Tilt- and Focal Series	548
<i>Tim Dahmen, Jean-Pierre Baudoin, Andrew R. Lupini, Christian Kübel, Philipp Slusallek, and Niels de Jonge</i>	

Utilization of Optical Polarization Microscopy in the Study of Sorption Characteristics of Wound Dressing Host Materials	561
<i>Miha Devetak, Zdenka Peršin, Karin Stana-Kleinschek, and Uroš Maver</i>	

Multi-Scale Visualization of Dynamic Changes in Poplar Cell Walls during Alkali Pretreatment	566
<i>Zhe Ji, Jianfeng Ma, and Feng Xu</i>	

MATERIALS APPLICATIONS

Simultaneous Hydrogen and Heavier Element Isotopic Ratio Images with a Scanning Submicron Ion Probe and Mass Resolved Polyatomic Ions	577
<i>Georges Slodzian, Ting-Di Wu, Noémie Bardin, Jean Duprat, Cécile Engrand, and Jean-Luc Guerquin-Kern</i>	

Application of Dynamic Impedance Spectroscopy to Scanning Probe Microscopy	582
<i>Mateusz Tomasz Tobiszewski, Anna Arutunow, and Kazimierz Darowicki</i>	

Surface Charge and Carbon Contamination on an Electron Beam Irradiated Hydroxyapatite Thin Film Investigated by Photoluminescence and Phase Imaging in Atomic Force Microscopy	586
<i>Radu Hristu, Denis E. Tranca, Stefan G. Stanciu, Maros Gregor, Tomas Plecenik, Martin Truchly, Tomas Roch, Syed A. M. Tofail, and George A. Stanciu</i>	

Characterization of Fibrous Mimeticite	596
<i>Vincent Thiéry</i>	

Performance of High-Resolution SEM/EDX Systems Equipped with Transmission Mode (TSEM) for Imaging and Measurement of Size and Size Distribution of Spherical Nanoparticles	602
<i>Vasile-Dan Hodoroaba, Charles Motzkus, Tatiana Macé, and Sophie Vaslin-Reimann</i>	

Aberration-corrected X-ray Spectrum Imaging and Fresnel Contrast to Differentiate Nanoclusters and Cavities in Helium-Irradiated Alloy 14YWT	613
<i>Chad M. Parish and Michael K. Miller</i>	

The Importance of Averaging to Interpret Electron Correlographs of Disordered Materials	627
<i>Tao Sun, Michael M.J. Treacy, Tian Li, Nestor J. Zaluzec, and J. Murray Gibson</i>	

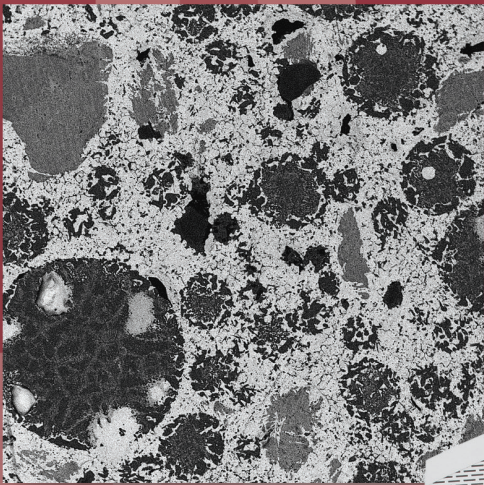
Sectioning of Individual Hematite Pseudocubes with Focused Ion Beam Enables Quantitative Structural Characterization at Nanometer Length Scales	635
<i>Emily Asenath-Smith and Lara A. Estroff</i>	

BOOK REVIEW

<i>Helium Ion Microscopy, Principles and Applications</i> , by David C. Joy	645
<i>Michael T. Postek</i>	

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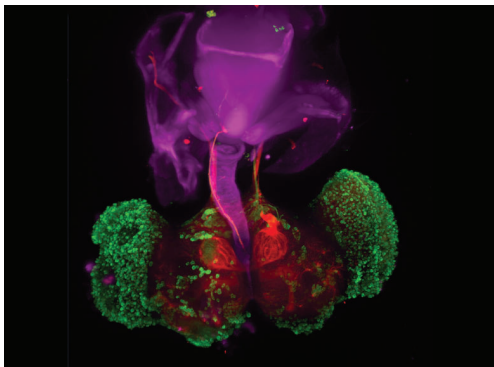
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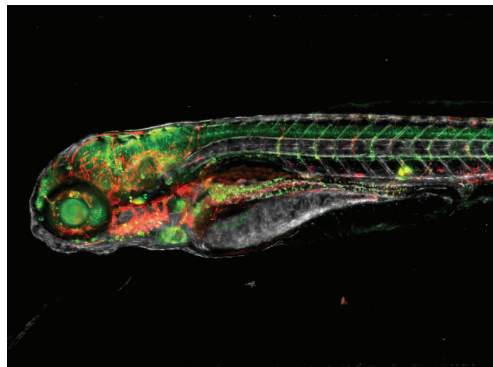
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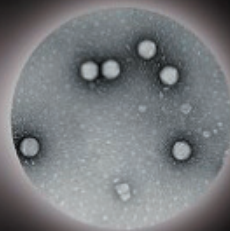
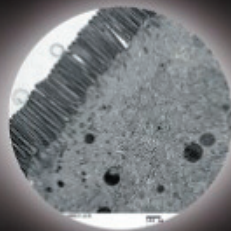
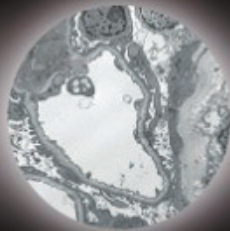
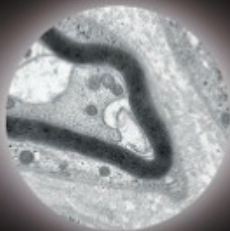
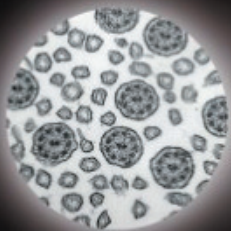


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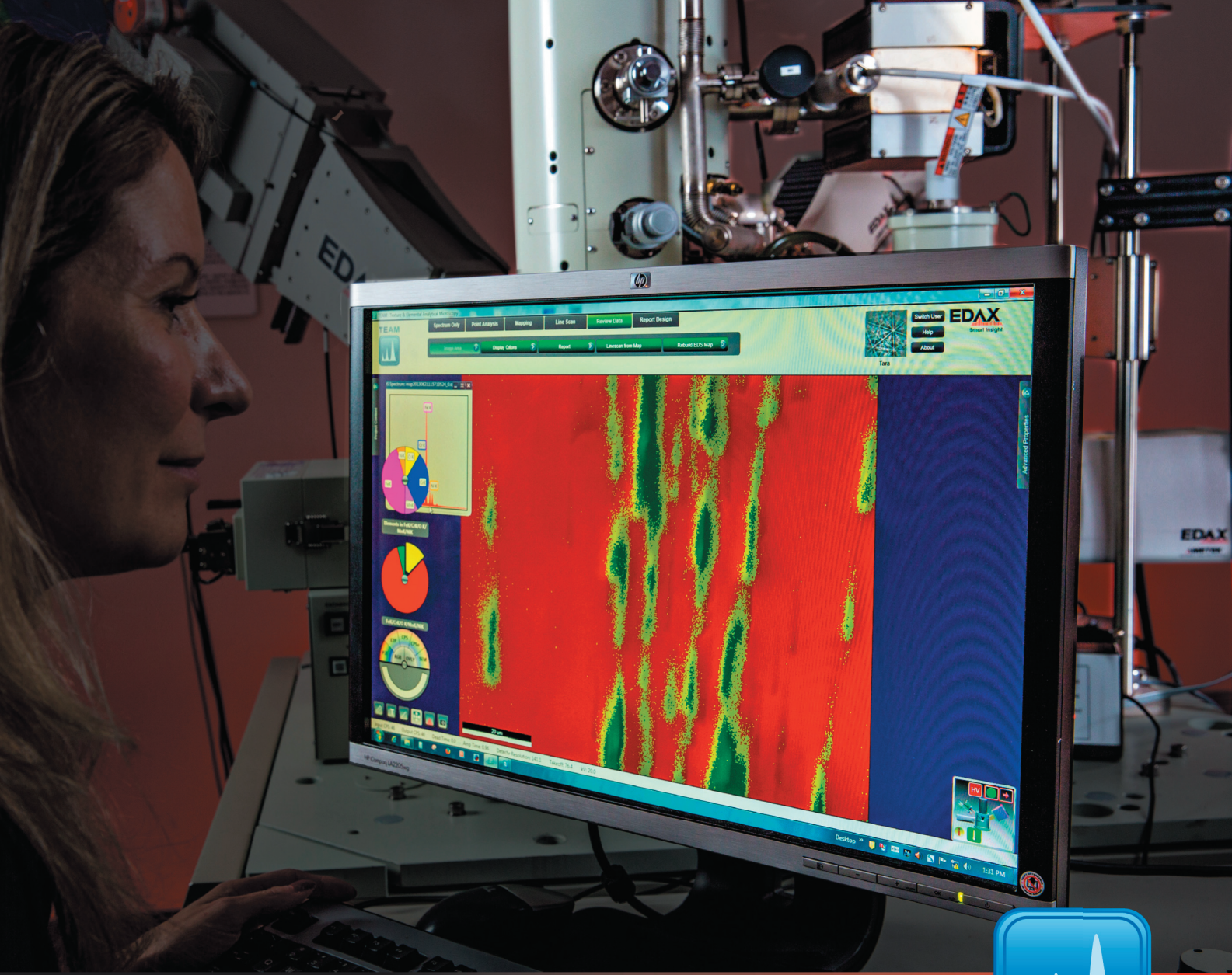


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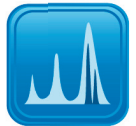
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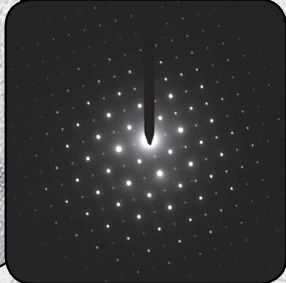
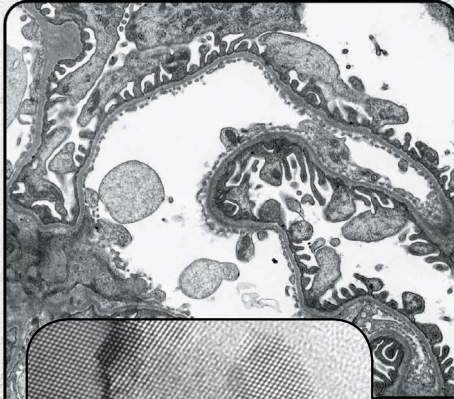
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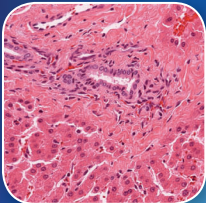
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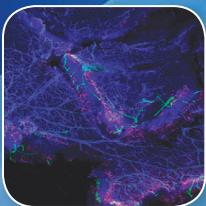
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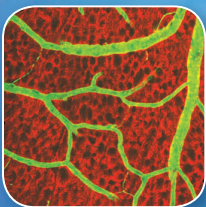


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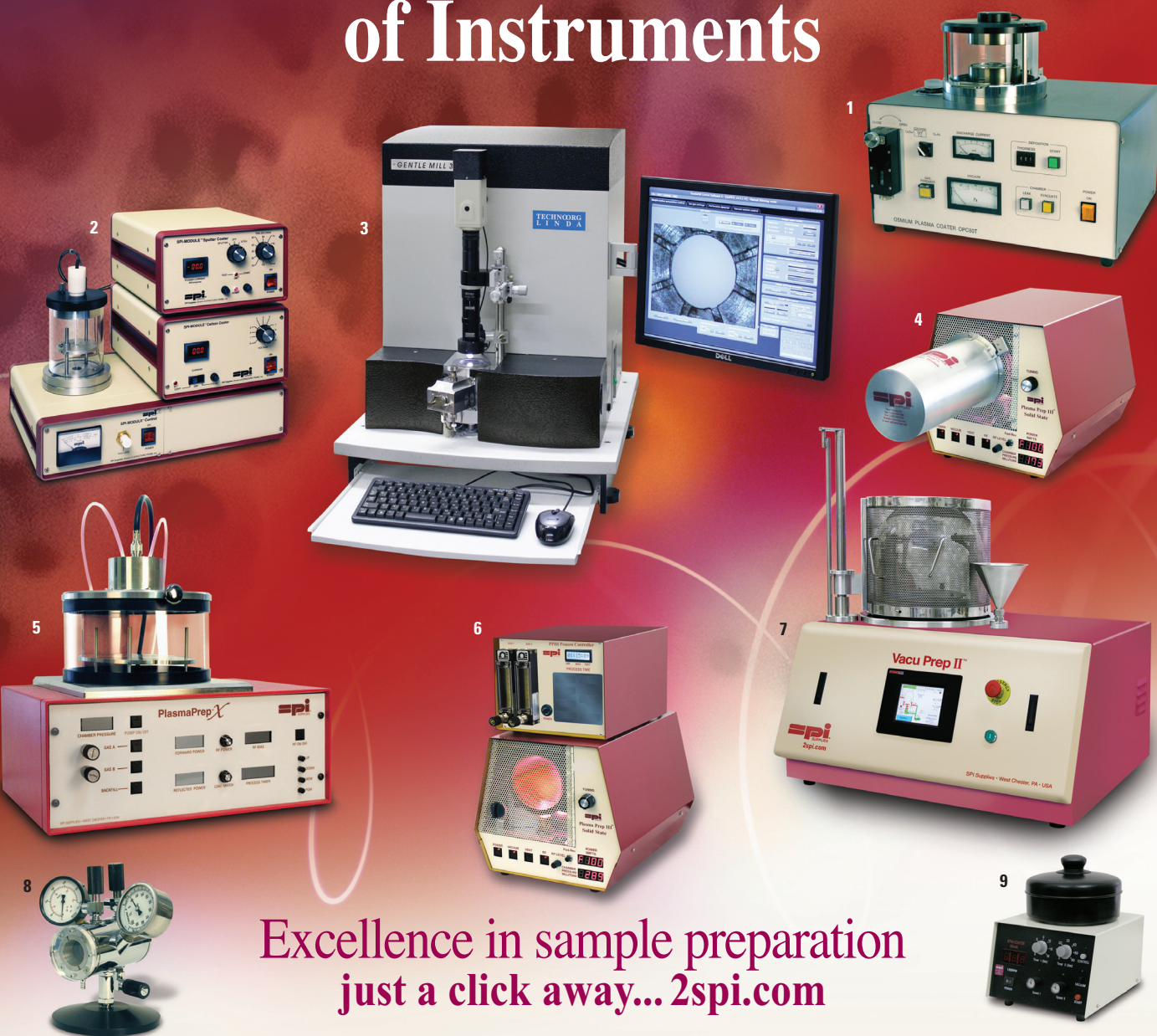
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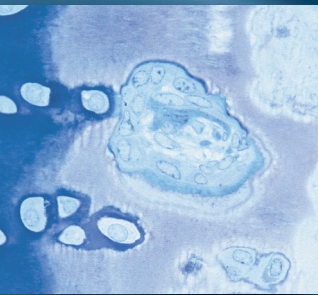
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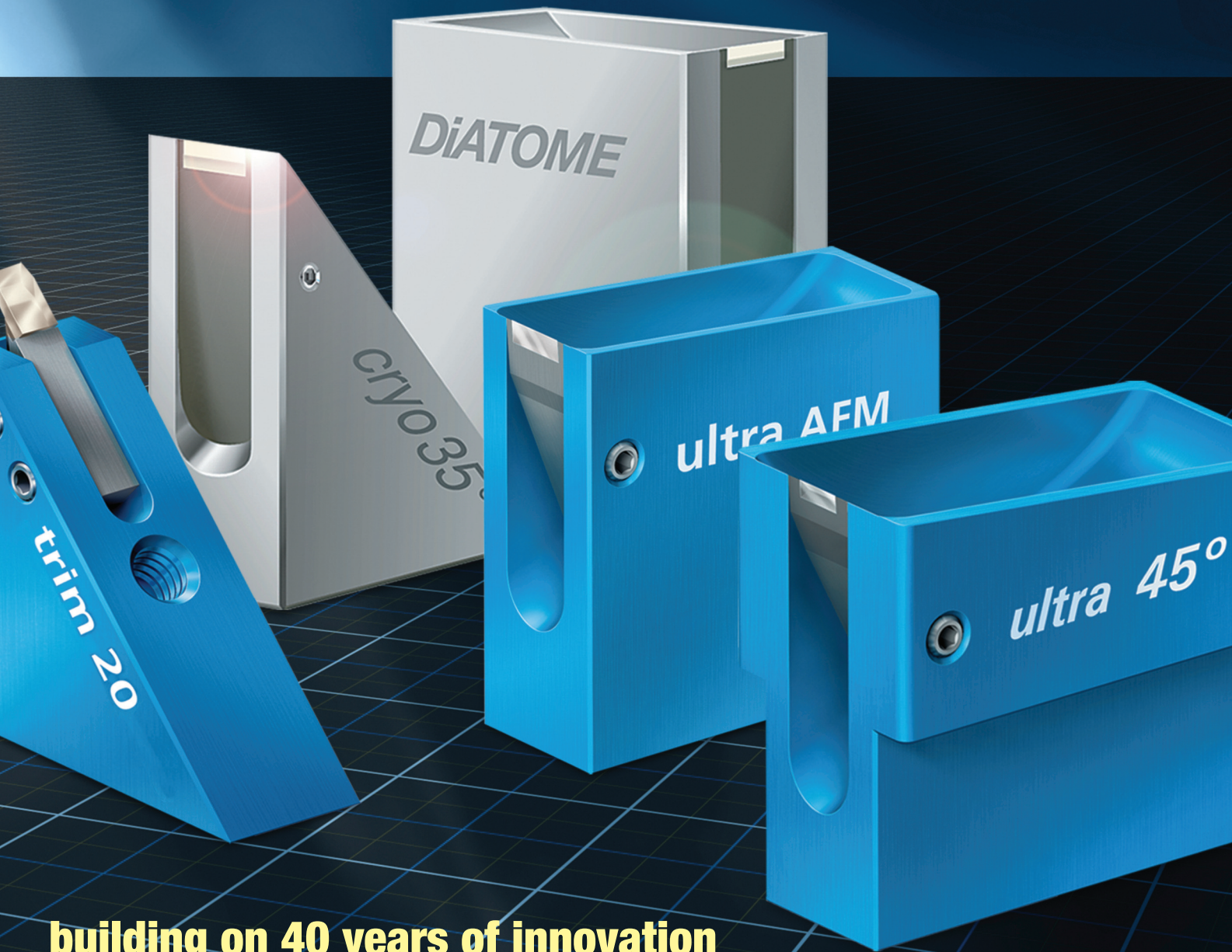
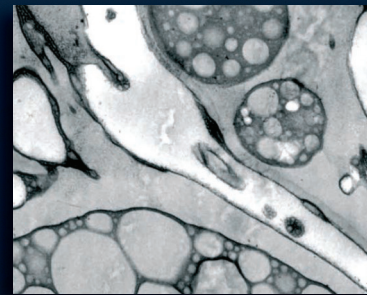
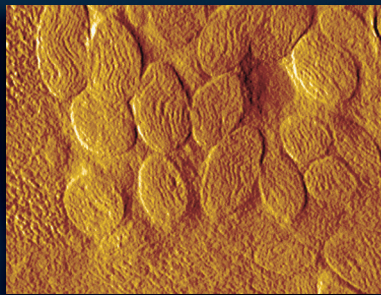
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